

## On the Roles of $\text{Bi}_2\text{Sr}_2\text{CuO}_x$ in $\text{Bi}_2\text{Sr}_2\text{CaCu}_2\text{O}_x/\text{Ag}$ Round Wire Transport on Multiple Length Scales

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**Abstract** - Despite 25 years of significant improvements in the performance of  $\text{Bi}_2\text{Sr}_2\text{CaCu}_2\text{O}_x$  ( $\text{Bi}2212$ )/Ag multifilamentary round wires (RWs), understanding the impact of microstructural defects, on multiple length scales, on the transport behavior remains a significant challenge. In melt-processed multifilamentary RWs the primary impurity is  $\text{Bi}_2\text{Sr}_2\text{CuO}_x$  ( $\text{Bi}2201$ ) which forms as mesoscopic grains and nanoscopic intergrowths. Here, the effect of  $\text{Bi}2201$  grains on transport are analyzed quantitatively using a statistical approach in which filaments are categorized based on the predominant phases observed by cross-sectional scanning electron microscopy. It is found that critical current density ( $J_c$ ) is inversely proportional to the percentage of filaments containing large  $\text{Bi}2201$  grains.  $\text{Bi}2212$  intergrowths are studied with atomic resolution aberration corrected scanning transmission electron microscope (STEM). Insight into the roles of  $\text{Bi}2201$  intergrowths is obtained by relating the STEM results to the  $\text{Bi}2212$  coherence length ( $\xi$ ), anisotropic magnetization behavior and magnetic-field dependent electrical transport.  $\text{Bi}2201$  intergrowths are shown to play a complex role in  $\text{Bi}2212/\text{Ag}$  wire transport through their impact on c-axis transport and flux pinning depending on the length scale.